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Application/Control No.	Applicant(s)/Patent under Reexamination
10/767,230	OHNISHI ET AL.
Examiner	Art Unit
Andy Huynh	2818

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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(INCLUDING SEARCH	STRATEGY	)
	DATE	EXMR
EAST 257/E21.277,758-760,762,763,751 (text search-see search histotry printout)	11/4/2005	AH
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Intereference Search History Printout	11/4/2005	АН